POLITECNICO DI MILANO

COMPUTER INFRASTRUCTURE CHEAT SHEET

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1 Performance evaluation

1.1 General

- 1. $\lambda_K = \frac{A_K}{T}$, $\lambda := \operatorname{arrival} \operatorname{rate}$, $A_K := \operatorname{num} \operatorname{of} \operatorname{arrivals}$
- 2. $X_K = \frac{C_K}{T}, \ X_K := throughput, C_K := num \ of \ completions$
- 3. $U_K = \frac{B_K}{T}, \ U_K := utilization, B_K := busy time$
- 4. $S_K = \frac{B_K}{C_K} = \frac{U_k T}{C_K}, \ S_K := service \ requirement \ per \ visit$
- 5. $N = \frac{W}{T}, \ N := customer \ population, W := accumulated \ systime$
- 6. $R_K = \frac{W}{C_K}$, $R_K := residence time$
- 7. $V_K = \frac{C_K}{C}$, $v_K := visits$
- 8. $D_K = V_K S_K = \frac{B_K}{C}$, $D_K := demand$

1.2 Utilization Law

$$U_K = X_K S_K = X D_K$$

1.3 Little's Law

$$N = XR$$

1.4 Response Time Law

$$R = \frac{N}{X} - Z, \ Z := think \, time$$

1.5 Forced Flaw Law

$$X_K = V_K X$$

1.6 Performace Bounds (Closed Models)

- 1. $D = \sum_{k=1}^{K} D_{K}$
- 2. $D_{max} = \max_K D_K$
- 3. $N^* = \frac{D+Z}{D_{max}}$

1.7 Throughput Bounds

1.7.1 Batch

$$\frac{1}{D} \le X(N) \le \min\left(\frac{N}{D}, \frac{1}{D_{max}}\right)$$

1.7.2 Terminal

$$\frac{N}{ND+Z} \le X(N) \le \min\left(\frac{N}{D+Z}, \frac{1}{D_{max}}\right)$$

1.7.3 Transaction

$$X(\lambda) \le \frac{1}{D_{max}}$$

1.8 Response Time Bounds

1.8.1 Batch

$$\max(D, ND_{max}) \le R(N) \le ND$$

1.8.2 Terminal

$$\max(D, ND_{max} - Z) \le R(N) \le ND$$

1.8.3 Transaction

$$D \leq R(\lambda)$$

1.9 Performace Bounds (Open Models)

1.
$$X(\lambda) \leq \frac{1}{D_{max}}$$

2.
$$\frac{D}{1-\lambda D_{avg}} \le R(\lambda) \le \frac{D}{1-\lambda D_{max}}$$

3.
$$\lambda_{sat} = \frac{1}{D_{max}}$$

2 Virtualization

2.1 Virtual istruction performace

 $T_v = T_p(1+p_po_p), \ T_v := time\ to\ run\ in\ virtual\ env, \ T_p := time\ to\ run\ in\ physical\ env,\ p_p := privileged\ instruction,\ o_p := overhead\ execution$

3 Disks

3.1 Disks performance

- 1. $T = (1-l)(N)(T_s+T_L)+T_T+T_c$, T := service time, $T_s := seek time$, $T_L := latency time$, $T_C := controller time$, $T_T := transfer time$, N := number of blocks, l := latency
- 2. $T_T = \frac{S}{r_t}$, S := total file size, $r_t = transfer rate$

3.
$$T_L = \frac{1}{RoundPerSecond}$$

3.2 RAID

3.2.1 RAID 0

Striping only, no redundancy (the more disks, the more probability to lose data, the better performaces)

$$MTTDL = \frac{MTTF}{n}$$

3.2.2 RAID 1

Mirroring, no striping (usually two disks) $MTTDL = \frac{MTTF^n}{2MTTR^{(n-1)}}$

3.2.3 RAID 1+0

Striping first, second mirroring (at least 4 disk, even number) $MTTDL = \frac{MTTF^2}{nMTTR}$

3.2.4 RAID 0+1

Mirroring first, second striping (at least 4 disk, even number)

$$MTTDL = \frac{2MTTF^2}{n^2MTTR}$$

3.2.5 RAID 5

block interland distributed parity (support one disk fails) (at least 3 disks)

$$MTTDL = \frac{MTTF^2}{n(n-1)MTTR}$$

$$P = \sum_{i=0}^{(n-1)} D_i$$

3.2.6 RAID 6

block interland distributed parity (support two disks fail) (at least 4 disks)

MTTDL =
$$\frac{MTTF^3}{n(n-1)(n-2)MTTR^2}$$

$$P = \sum_{i=0}^{(n-1)} D_i$$

$$Q = \sum_{i=0}^{(n-1)} gD_i, g \neq 1$$

3.3 Dependability exponential distribution

1.
$$F(t) = 1 - e^{-\lambda t} = 1 - e^{-\frac{t}{MTTF}} := unreliability$$

2.
$$f(t) = \lambda e^{-\lambda t} = \frac{e^{-\frac{t}{MTTF}}}{MTTF} := density function of fails$$

3.
$$R(t) = e^{-\lambda t} = e^{-\frac{t}{MTTF}} := reliability$$

4.
$$MTTF = \mathbb{E}[X] = \frac{1}{\lambda}$$

5. if
$$t \ll MTTF \implies F(t) \approx \frac{t}{MTTF}$$

3.4 Not repairable failure

3.4.1 Serial components

- 1. $R(t) = \prod_{i=1}^{n} R_i(t)$
- 2. $MTTF_{serie} = \frac{1}{\sum_{i=1}^{n} \frac{1}{MTTF_i}}$
- 3. if $MTTF_1 = ... = MTTF_n \implies MTTF_{serie} = \frac{MTTF}{n}$

3.4.2 Parallel components

- 1. $R(t) = 1 \prod_{i=1}^{n} (1 R_i(t))$
- 2. $MTTF_{parallel} = \sum_{i=1}^{n} MTTF_i \frac{1}{\sum_{i=1}^{n} \frac{1}{MTTF_i}} = \sum_{i=1}^{n} MTTF_i MTTF_{serie}$
- 3. if $MTTF_1 = \ldots = MTTF_n \implies MTTF_{parallel} = MTTF(\sum_{i=1}^n \frac{1}{i})$

3.5 Repairable failure

- $1. \ MTBF := mid \ time \ between \ failure = MTTR + MTTF$
- 2. $A := Availability = \frac{MTTF}{MTTR + MTTF} = \frac{MTTF}{MTRF}$

3.5.1 Serial components

- 1. $A = \prod_{i=1}^{n} A_i$
- 2. $A_{serie} = \prod_{i=1}^{n} \frac{MTTF_i}{MTTF_i + MTTR_i}$
- 3. $MTTF_{serie} = \frac{1}{\sum_{i=1}^{n} \frac{1}{MTTF_i}}$
- 4. $MTTR_{serie} = \frac{(1 A_{serie})MTTF_{serie}}{A_{serie}}$

3.5.2 Parallel components

- 1. $A = 1 \prod_{i=1}^{n} (1 A_i)$
- 2. $A_{parallel} = 1 \prod_{i=1}^{n} (1 \frac{MTTF_i}{MTTF_i + MTTTR_i})$
- 3. $MTTF_{parallel} = \frac{A_{parallel}MTTR_{parallel}}{1 A_{parallel}}$
- 4. $MTTR_{parallel} = \frac{1}{\sum_{i=1}^{n} \frac{1}{MTTR_i}}$